

PNZ263L (PN263L-(NC))

Silicon planar type

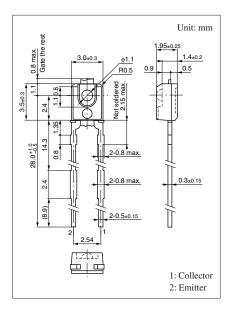
For optical control systems

■ Features

- Darlington output, high sensitivity
- Small size, thin side-view type package
- Adoption of visible light cutoff resin

■ Absolute Maximum Ratings $T_a = 25$ °C

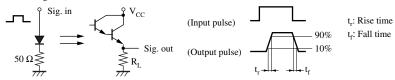
Parameter	Symbol	Rating	Unit	
Collector-emitter voltage (Base open)	V _{CEO}	20	V	
Emitter-collector voltage (Base open)	V _{ECO}	5	V	
Collector current	I_C	30	mA	
Collector power dissipation	P _C	100	mW	
Operating ambient temperature	Topr	-25 to +80	°C	
Storage temperature	T _{stg}	-30 to +100	°C	



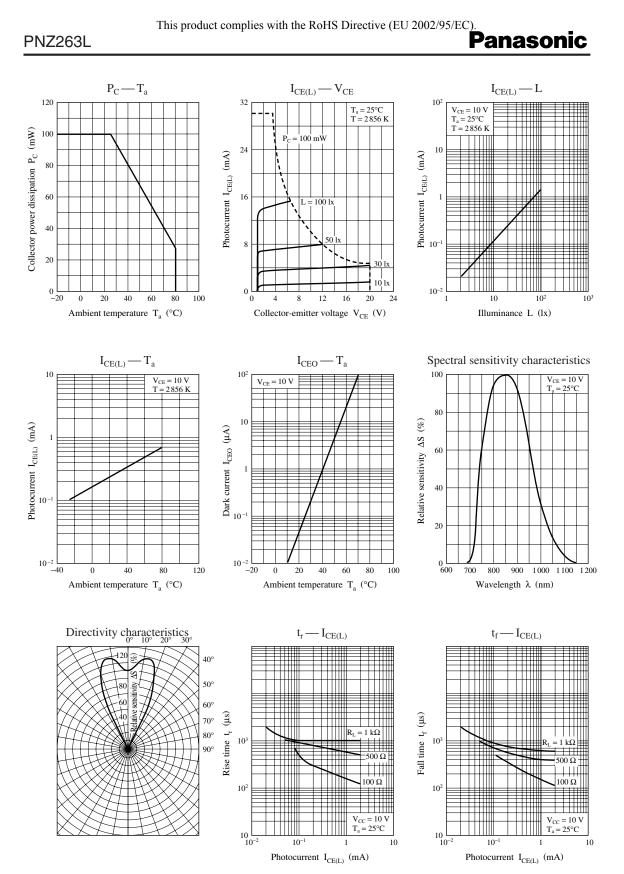
■ Electrical-Optical Characteristics $T_a = 25$ °C ± 3 °C

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Sensitivity to infrared radiation *1	S _{IR}	$V_{CE} = 10 \text{ V}, H = 3.75 \ \mu\text{W/cm}^2$	100	250	500	μΑ
Dark current	I_{CEO}	$V_{CE} = 10 \text{ V}$		0.1	0.50	μΑ
Peak emission wavelength	λ_{p}	$V_{CE} = 10 \text{ V}$		850		nm
Half-power angle	θ	The angle from which photocurrent becomes 50%		25		0
Rise time *2	t _r	$V_{CC} = 10 \text{ V}, I_{C} = 1 \text{ mA}, R_{L} = 100 \Omega$		150		μs
Fall time *2	t _f			150		μs
Collector-emitter saturation voltage *1	V _{CE(sat)}	$I_C = 100 \mu A, H = 3.75 \mu W/cm^2$		0.7	1.5	V

- Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.
 - 2. Spectral sensitivity characteristics: Sensitivity for wave length over 400 nm maximum sensitivity ratio is 100%.
 - 3. This device is designed be disregarded radiation.
 - 5. *1: Source: Infrared radiation ($\lambda = 940 \text{ nm}$)
 - *2:Switching time measurement circuit



Note) The part number in the parenthesis shows conventional part number.



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